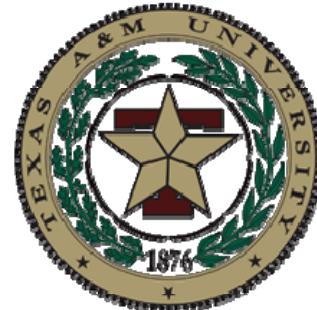


# ECEN474: (Analog) VLSI Circuit Design

## Fall 2011

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### Lecture 2: MOS Transistor Modeling



Sebastian Hoyos

Analog & Mixed-Signal Center  
Texas A&M University

# Announcements

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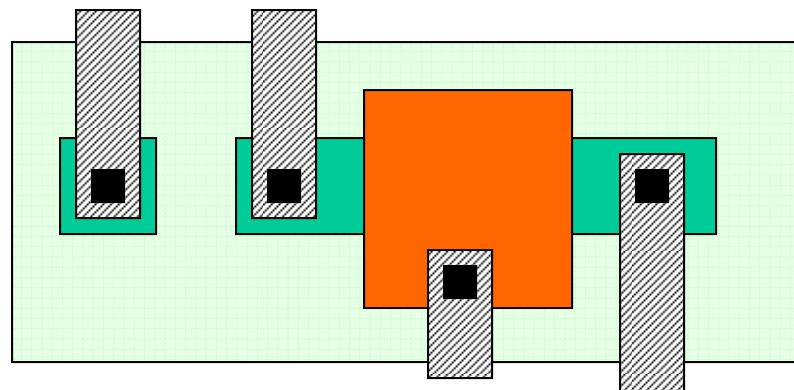
- No Lab this week
  - Lab 1 next week
- Current Reading
  - Razavi's CMOS book chapter 2

# Agenda

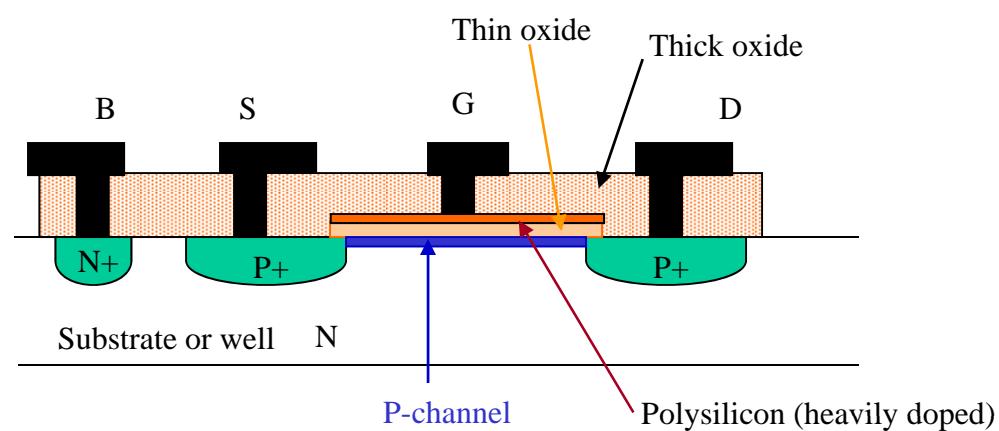
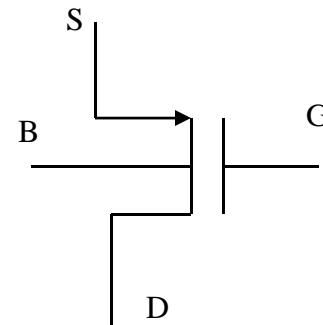
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- MOS Transistor Modeling
  - DC I-V Equations
  - Threshold Voltage,  $V_T$

# MOS Transistor



**P-type transistor**



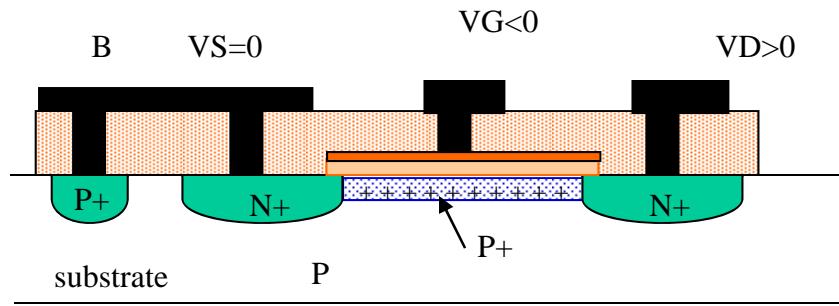
**BASIC IDEA:**

**SOURCE-DRAIN CURRENT IS CONTROLLED BY THE SOURCE-GATE VOLTAGE.**

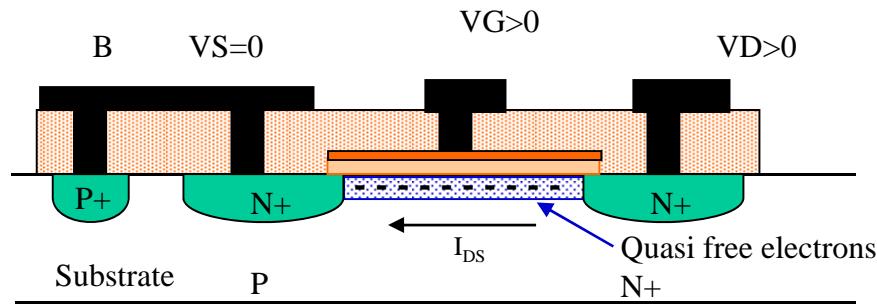
The system is “isolated” if the diodes are biased in reverse region by using the Bulk terminal.

# MOS Transistor

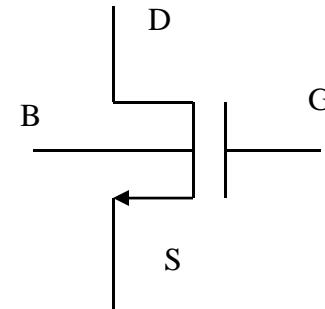
Accumulation: Two diodes back to back  
**D-S current is zero**



Inversion: Channel is connecting D and S  
**D-S current is possible**



## N-type transistor



Under this condition, there are 3 possible applications:

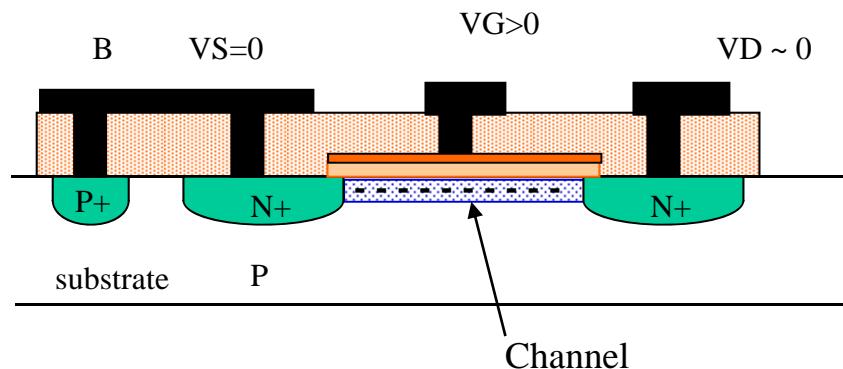
**Subthreshold** (extremely low-voltage low-power applications)

**Linear region** (voltage controlled resistor, linear OTA's, multipliers, switches)

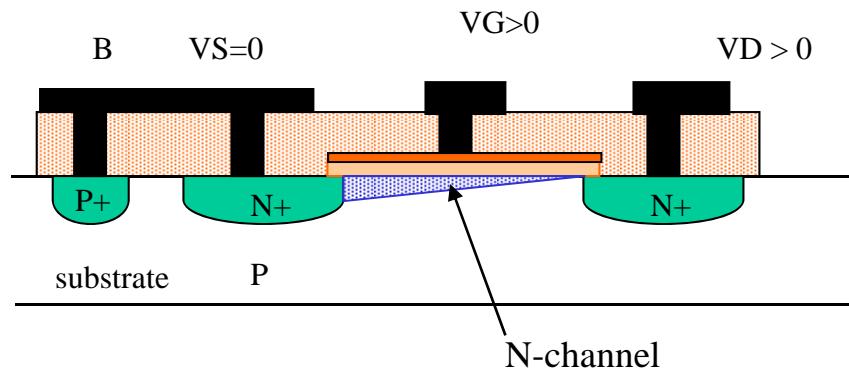
**Saturation region** (Amplifiers)

# MOS Transistor

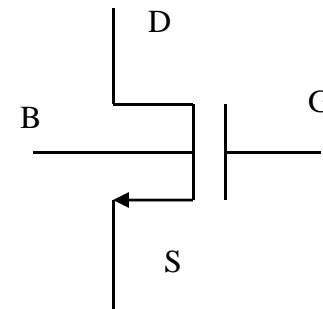
Triode Region (D-S channel is complete)



Saturation Region (D-S channel is incomplete)



**N-type transistor**



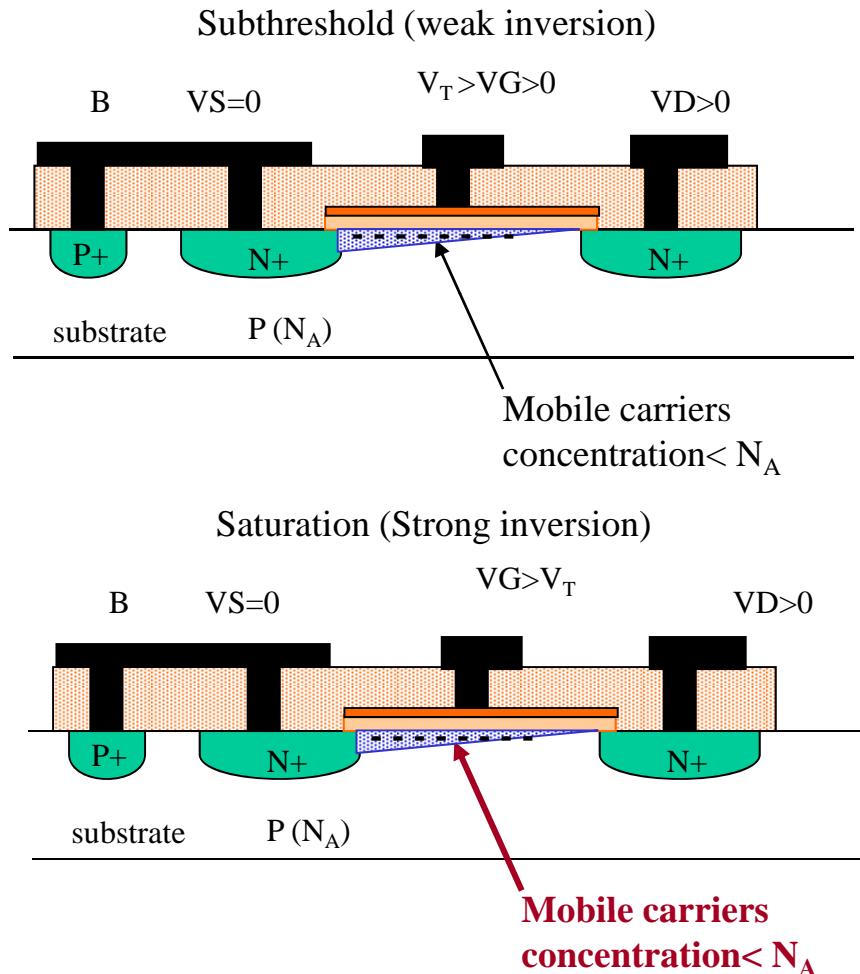
In this condition, there are 3 possible applications:

**Subthreshold** (extremely low-voltage low-power applications)

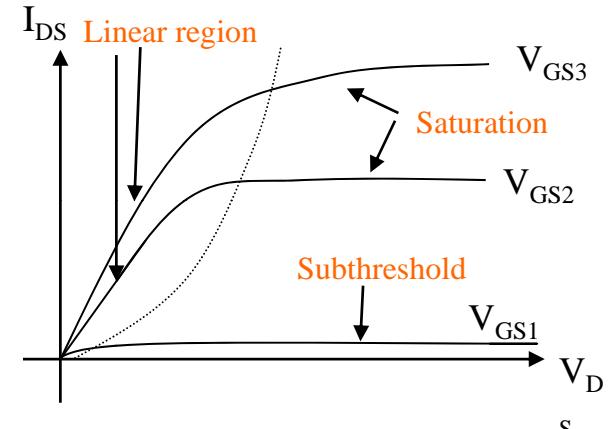
**Linear region** (voltage controlled resistor, linear OTA's, multipliers)

**Saturation region** (Amplifiers)

# MOS Transistor



## N-type transistor

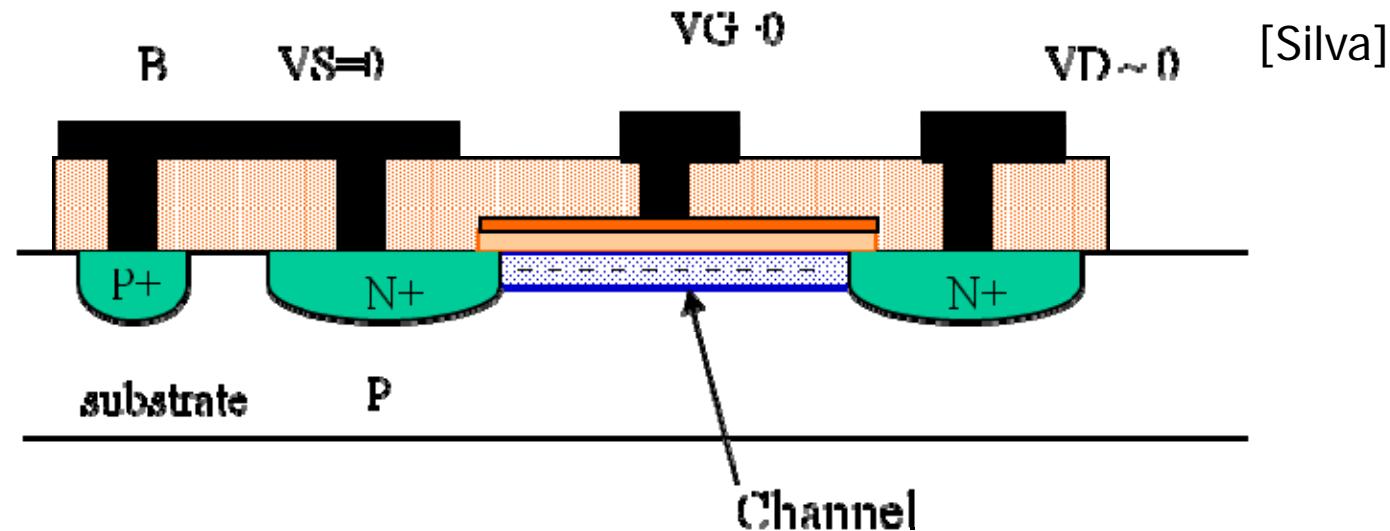


**Subthreshold** (extremely low-voltage low-power applications)

**Linear region** (voltage controlled resistor, linear OTA's, multipliers)

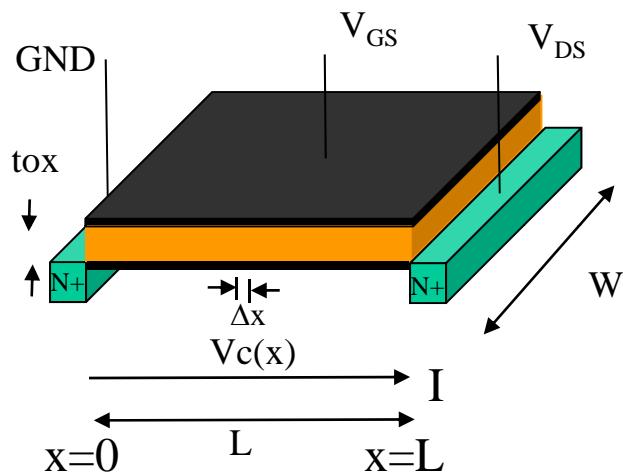
**Saturation region** (Amplifiers)

# $V_T$ Definition



- The threshold voltage,  $V_T$ , is the voltage at which an “inversion layer” is formed
  - For an NMOS this is when the concentration of electrons equals the concentration of holes in the p<sup>-</sup> substrate

## MOS Equations in Linear Region



$$I = Q_d v$$

Source-Drain Current

$$Q_d(x) = WC_{ox} (V_{GC} - V_T)$$

Incremental Charge Density

$$V_{GC} - V_T = V_{GS} - V_{CS}(x) - V_T$$

Gate-channel Voltage

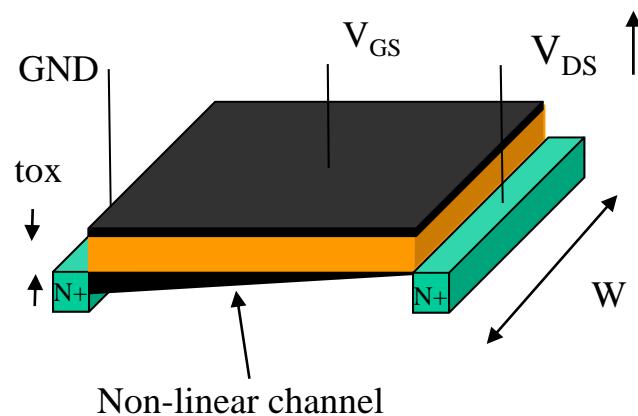
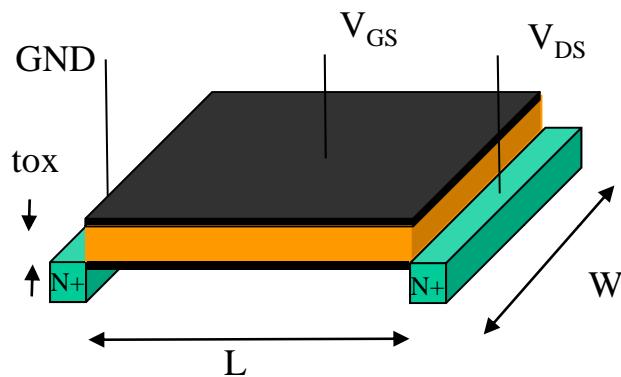
$$I_D = -WC_{ox} (V_{GS} - V_{CS}(x) - V_T) v$$

Drain-Source Current

$$I_D = WC_{ox} (V_{GS} - V_{CS}(x) - V_T) \mu_n \frac{dV(x)}{dx}$$

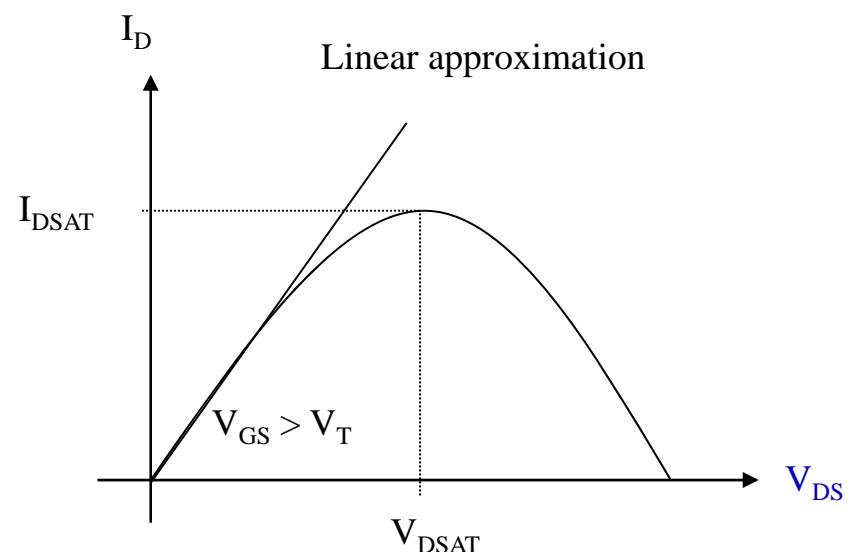
$$\int_{x=0}^L I_D dx = \int_{V=V_S}^{V_D} WC_{ox} (V_{GS} - V_{CS}(x) - V_T) \mu_n dV$$

## MOS Equations in **Linear Region**

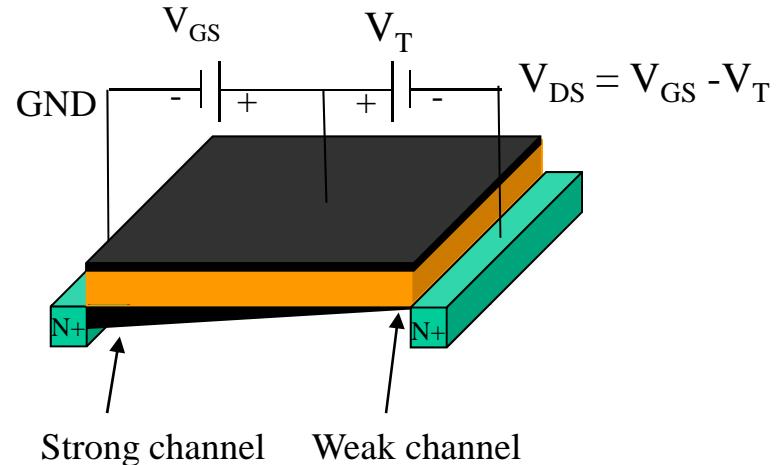


Drain current: Expression used in SPICE level 1

$$I_D = \frac{W}{L} \mu_n C_{ox} (V_{GS} - V_T - 0.5V_{DS}) V_{DS}$$

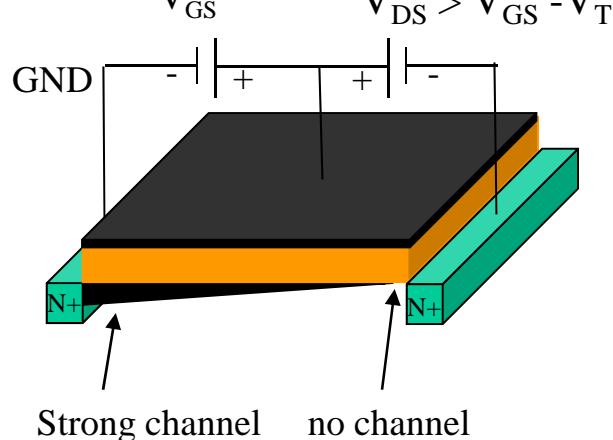


## MOS Equations in **Saturation and Linear Region**



Under these conditions → current is highest

$$I_D = \frac{W}{2L} \mu_n C_{OX} (V_{GS} - V_T)^2$$



SATURATION REGION ( $V_{DS} > V_{GS} - V_T$ )

Carriers are attracted to the drain, and swept in the region where channel is incomplete (why???)

Current is till given by

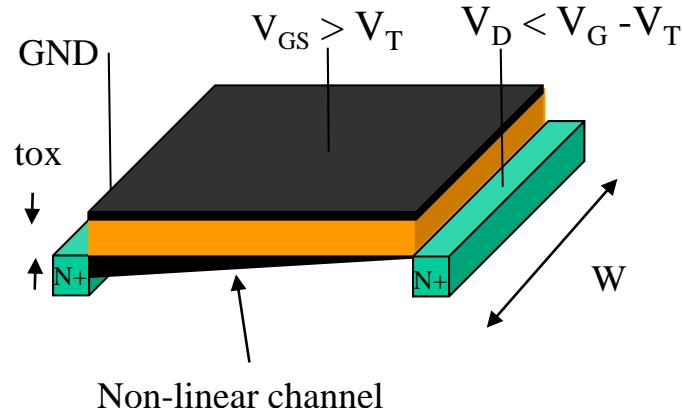
$$I_D = \frac{W}{2L} \mu_n C_{OX} (V_{GS} - V_T)^2$$

or

$$I_{DSAT} = \frac{W}{2L} \mu_n C_{OX} (V_{DSAT})^2$$

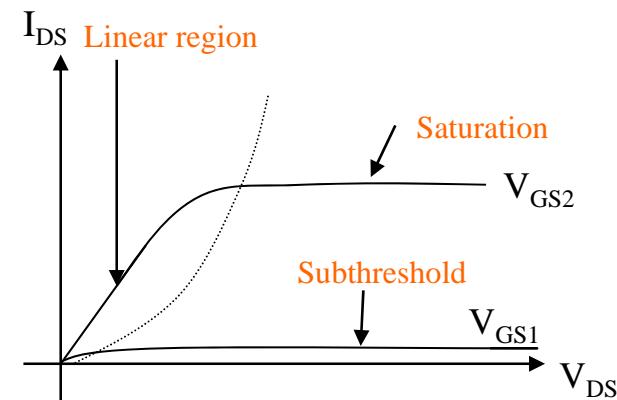
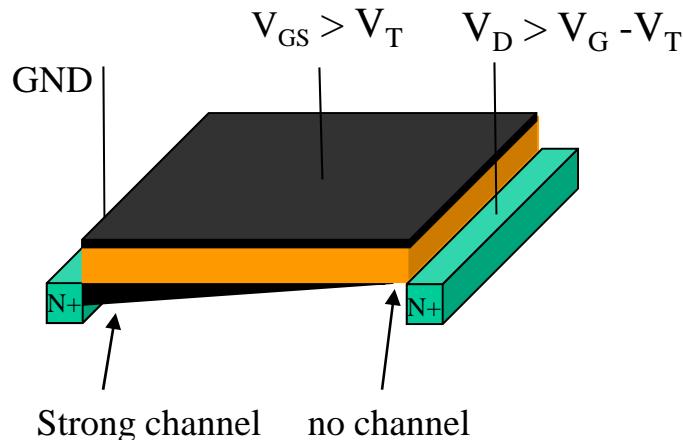
SPICE level 1

## MOS Equations in **Saturation and Linear Region: $V_{GS} > V_T$**



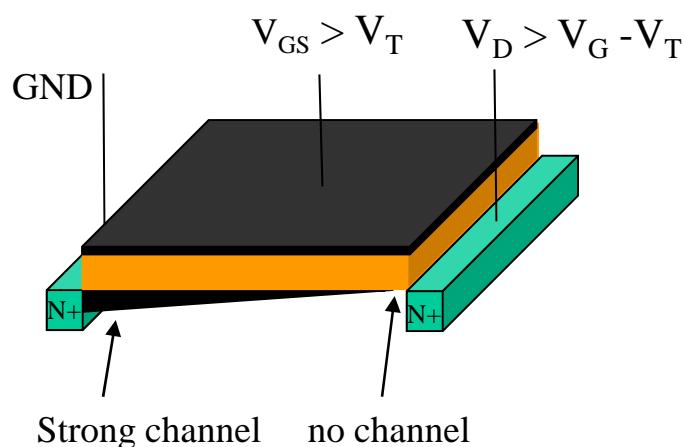
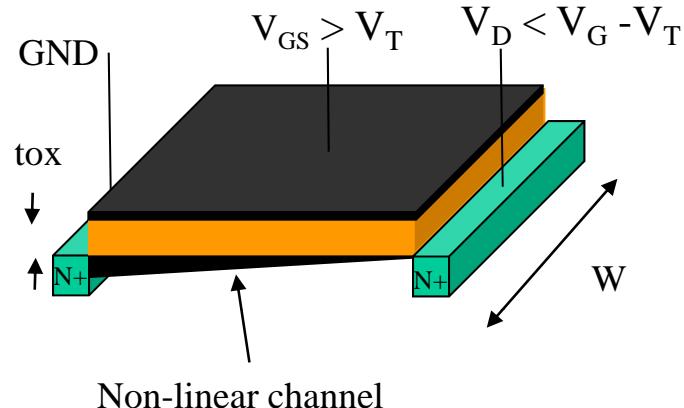
**Linear region:**  $I_D = \frac{W}{L} \mu_n C_{OX} (V_{GS} - V_T - 0.5V_{DS}) V_{DS}$

**Saturation region:**  $I_D = \frac{W}{2L} \mu_n C_{OX} (V_{GS} - V_T)^2$



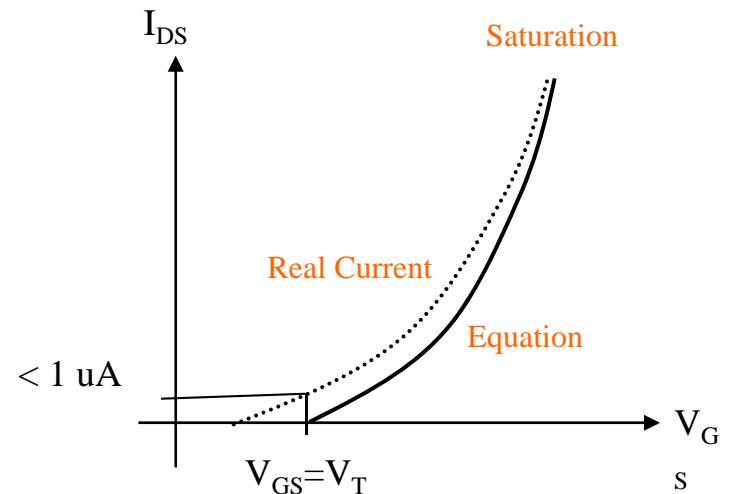
**N-type transistor**

## MOS Equation in **Saturation** : $V_{GS} > V_T$



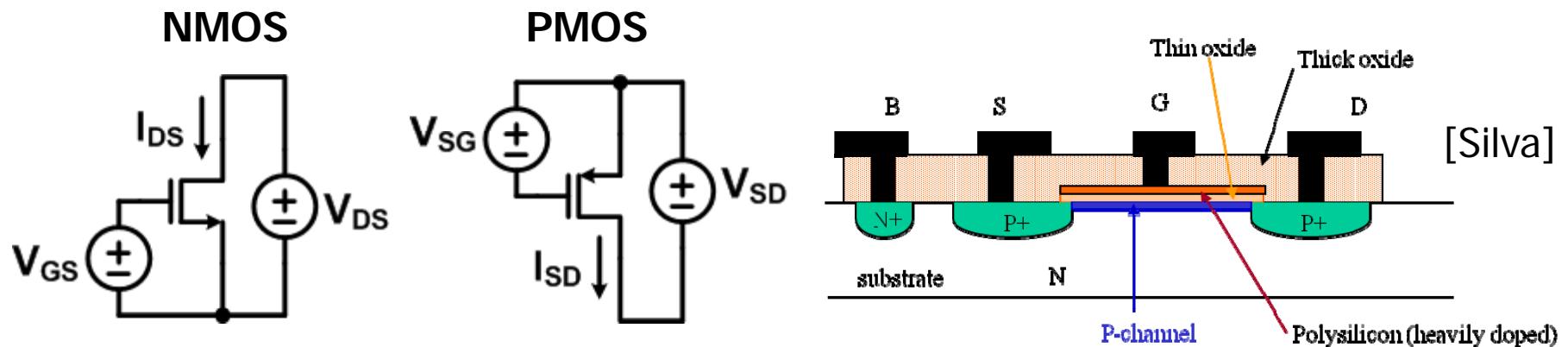
**Linear region:**  $I_D = \frac{W}{L} \mu_n C_{OX} (V_{GS} - V_T - 0.5V_{DS}) V_{DS}$

**Saturation region:**  $I_D = \frac{W}{2L} \mu_n C_{OX} (V_{GS} - V_T)^2$



**N-type transistor: saturation**

# What about the PMOS device?



- The current equations for the PMOS device are the same as the NMOS **EXCEPT** you swap the current direction and all the voltage polarities

**NMOS**

$$\text{Linear: } I_{DS} = \frac{W}{L} \mu_n C_{ox} (V_{GS} - V_{Tn} - 0.5V_{DS}) V_{DS}$$

$$\text{Saturation: } I_{DS} = \frac{W}{2L} \mu_n C_{ox} (V_{GS} - V_{Tn})^2$$

**PMOS**

$$I_{SD} = \frac{W}{L} \mu_p C_{ox} (V_{SG} - |V_{Tp}| - 0.5V_{SD}) V_{SD}$$

$$I_{SD} = \frac{W}{2L} \mu_p C_{ox} (V_{SG} - |V_{Tp}|)^2$$

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## MOS MODEL: SPICE LEVEL-II

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• Drain current, Triode region

$$\text{NMOS : } I_{DS} = \frac{W}{L} \mu_n C_{OX} (V_{GS} - V_{Tn} - 0.5V_{DS}) V_{DS}$$

$$\text{PMOS : } I_{SD} = \frac{W}{L} \mu_p C_{OX} (V_{SG} - |V_{Tp}| - 0.5V_{SD}) V_{SD}$$

• Drain Current, Saturation region

$$\text{NMOS : } I_{DS} = \frac{W}{2L} \mu_n C_{OX} (V_{GS} - V_{Tn})^2$$

$$\text{PMOS : } I_{SD} = \frac{W}{2L} \mu_p C_{OX} (V_{SG} - |V_{Tp}|)^2$$

• Threshold voltage (zero bias)

$$V_{T0} = V_{FB} + 2\phi_F + \gamma \sqrt{2\phi_F}$$

• Threshold voltage

$$V_T = V_{T0} + \gamma [\sqrt{2\phi_F + V_{SB}} - \sqrt{2\phi_F}] \Rightarrow V_{T0} \Big|_{V_{SB}=0}$$

• KP and  $\gamma$  (Spice Model)

$$KP = \mu C_{OX}; \quad \gamma = \frac{\sqrt{2q\epsilon_{si}N_{Bulk}}}{C_{OX}}$$

# Next Time

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- MOS Transistor Modeling
  - Small-Signal Model
  - Spice Models